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|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/828,692 | | Applicant(s)/Patent Under Reexamination NEGISHI ET AL. | |
| | Examiner Michael Y. Won | | Art Unit 2155 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-2003/0033383 | 02-2003 | Elnozahy et al. | 709/219 |
| * | B | US-2004/0111486 | 06-2004 | Schuh et al. | 709/214 |
| * | C | US-6,792,424 | 09-2004 | Burns et al. | 707/9 |
| * | D | US-2005/0021657 | 01-2005 | Negishi et al. | 709/213 |
| * | E | US-6,868,439 | 03-2005 | Basu et al. | 709/213 |
| * | F | US-7,103,617 | 09-2006 | Phatak, Shirish Hemant | 707/201 |
| * | G | US-7,165,096 | 01-2007 | Soltis, Steven R. | 709/217 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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